

FDS6814

Dual N-Channel 2.5V Specified PowerTrench™ MOSFET

General Description

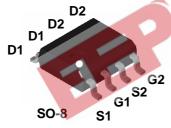
These N-Channel 2.5V specified MOSFETs are produced using a rugged gate version of Fairchild's advanced PowerTrench™ process. It has been optimized for power management applications which require a wide range of gate drive voltage.

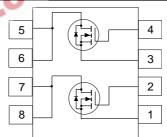
Applications

- Low voltage DC/DC Converters
- · Load switch
- · Battery protection
- · Power management

Features

- 8 A, 20 V. $R_{DS(ON)} = 0.020 \Omega @ V_{GS} = 4.5 V$ $R_{DS(ON)} = 0.030 \Omega @ V_{GS} = 2.5 V$
- Rugged gate rating (±12V).
- · Low gate charge.
- · Fast switching speed.
- · High performance trench technology for extremely $\text{low R}_{\text{\tiny DS(ON)}}$
- High power and current handling capability.





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	8	А
	- Pulsed		50	
P _D	Power Dissipation for Dual Operation		2.0	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

R _e JA	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _e JC	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

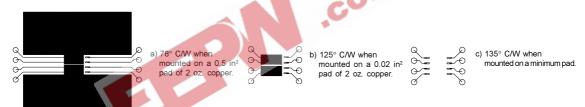
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Device Marking	Device	Reel Size	Tape width	Quantity
FDS6814	FDS6814	13"	12mm	2500 units

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Electrical Characteristics T_A=25°C unless otherwise noted

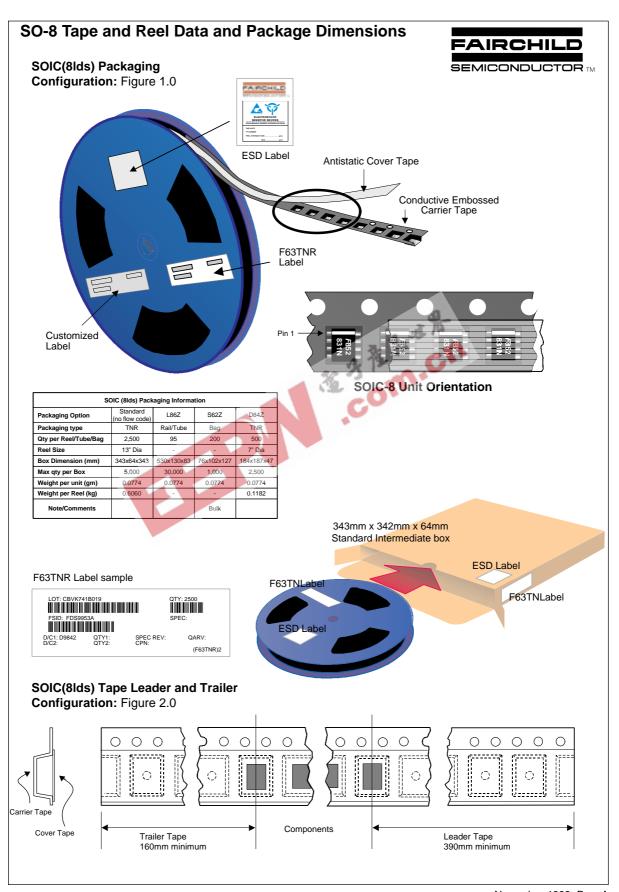
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
OFF CH	ARACTERISTICS		•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 12 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -12 V, V _{DS} = 0 V			-100	nA
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.6		1.5	l v
	RACTERISTICS (Note 2) Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	0.6	1 1	1.5	l v
	0: :: 0 : 0	1/ / - 1/ / - 0 /				
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 4.5 V, I _D = 8 A V _{GS} = 2.5 V, I _D = 6.5 A			0.02 0.03	Ω
$R_{DS(ON)}$ $I_{D(ON)}$,	25			Ω
I _{D(ON)}	On-Resistance On-State Drain Current SOURCE DIODE CHARACTE	$V_{GS} = 2.5 \text{ V}, I_D = 6.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, V_{DS} = 5.0 \text{ V}$ ERISTICS AND MAXIMUM I			0.03	A
I _{D(ON)}	On-Resistance On-State Drain Current	$V_{GS} = 2.5 \text{ V}, I_D = 6.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, V_{DS} = 5.0 \text{ V}$ ERISTICS AND MAXIMUM I				

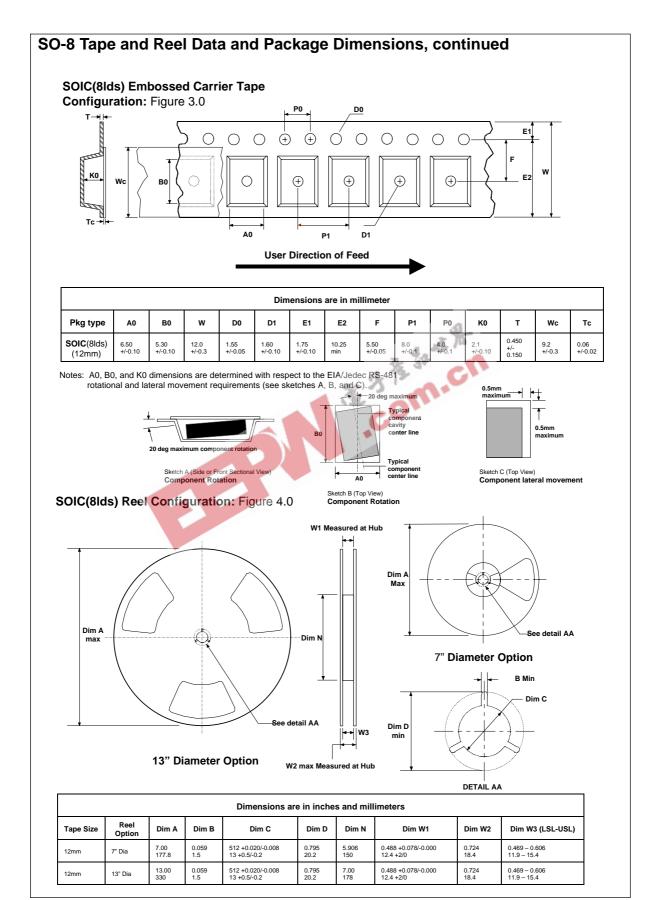
^{1.} R_{BUA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design. Thermal rating based on independent single device operation.

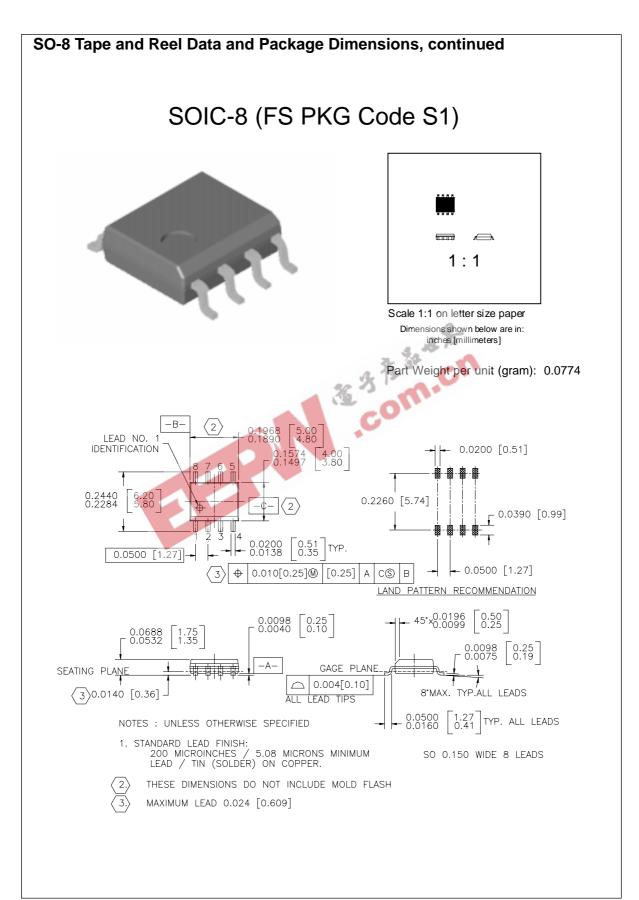


Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μs , Duty Cycle \leq 2.0%







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